

Applicant:	Kyocera	
FCC ID:	V65SCP-6760	
Report #:	CT-6760-20RF-0709-R0	

Hearing Aid Compatibility (HAC) RF Emissions

FCC 47 CFR Part 20.19

Test Report

For

Kyocera Corporation c/o Kyocera Communication Inc.

Product:Dual-Band CDMA PhoneModel:SCP-6760



Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

TABLE OF CONTENTS

1	รเ	UMMARY OF TESTING	4
2	EC	QUIPMENT UNDER TEST INFORMATION	4
3	TE	EST CONDITIONS	5
	3.1 3.2 3.3 3.4	AMBIENT CONDITIONS RF CHARACTERISTICS OF THE TEST SITE TEST SIGNAL, FREQUENCIES AND OUTPUT POWER EUT OPERATING CONDITIONS	
4	DE	ESCRIPTION OF TEST EQUIPMENT	7
	4.1 4.2 4.3 4.4	Test Equipment Used Near Field Measurement System Isotropic E-Field Probe Isotropic -Field Probe	7
5	S١	YSTEM VALIDATION	9
	5.1 5.2	DIPOLE VALIDATION SETUP DIPOLE VALIDATION RESULTS	
6	D	ESCRIPTION OF TEST PROCEDURE	11
	6.1 6.2 6.3	TEST POSITIONS RF EMISSION MEASUREMENTS REFERENCE AND PLANE RF EMISSIONS MEASUREMENT PROCEDURES	
7	PF	ROBE MODULATION FACTOR (PMF)	13
	7.1 7.2 7.3	PMF MEASUREMENT PROCEDURES PMF TEST RESULTS PMF PEAK POWER MEASUREMENT PLOTS	
8	EN	MISSION DATA EXTRACTION AND POSTPROCESSING	16
9	M	EASUREMENT UNCERTAINTY	17
10	D	RF EMISSIONS TESTS	
	10.1 10.2 10.3 10.4	CDMA 800 TEST RESULTS CDMA 1900 TEST RESULTS	
1′	1	APPENDIX A: PROBE CALIBRATION CERTIFICATION	
12	2	APPENDIX B: SYSTEM VALIDATION DATA PLOTS	24
13	3	APPENDIX C: TEST RESULTS/PLOTS	24
14	4	APPENDIX D: PHOTO TEST SETUP	24



ATTESTATION

The tested device complies with the requirements in respect of all parameters subject to the test. The test results and statements relate only to the items tested.

The test equipment used was suitable for the tests performed and within manufacturer's published specifications and operating parameters.

The test methods were consistent with the methods described in the relevant standards.

Product:	Dual-Band CDMA Cellular Phone with Bluetooth	
Model #:	SCP-6760	
FCC ID:	V65SCP-6760	
Tested in accordance with:	FCC 47 CFR Part 20.19	
	ANSI C63.19-2007	
Test performed by:	Comptest Services LLC	
Test Requested by:	KYOCERA Corporation	
	C/o KYOCERA Communication Inc	
	10300 Campus Point Drive	
	San Diego, CA 92121 United States	
Date of Test:	June 30, 2009 – July 1, 2009	

Responsible Engineer

Benjamin Nguyen

Benjamin Nguyen Test Engineer Reviewed and approved by:

Tammy To Quality Manager



SUMMARY OF TESTING

1

Rule Part	Test Description	Section #	Verdict
FCC § 20.19(b), §6.3(v), §7.3(v)	HAC RF Emissions	4	Pass
ANSI C63.19-2007 HAC M Category:			M4

2 EQUIPMENT UNDER TEST INFORMATION

Product:	Dual-Band CDMA Cellular Phone with Bluetooth	
FCC ID:	V65SCP-6760	
Model Number:	SCP-6760	
EUT Serial Number:	268435457816702550	
Туре:	[] Identical Prototype,	
	[X] Pre-Production,	
	[] Production	
Device Category:	Portable	
RF Exposure Environment:	General Population / Uncontrolled	
Antenna:	Internal	
Detachable Antenna:	Yes	
External Input:	Audio/Digital Data	
Quantity:	Quantity production is planned	
Modes:	800 CDMA	1900 CDMA
Multiple Access Scheme:	CDMA	CDMA
TX Frequency (MHz):	824 – 849	1850 - 1910
Rated RF Conducted Output Power (dBm)	25.0	24.8



Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

3 TEST CONDITIONS

3.1 Ambient Conditions

All tests were performed under the following environmental conditions:		
Ambient Temperature:	23 ± 2 Degrees C	
Tissue simulating liquid temperature:	22 ± 1 Degrees C	
Relative Humidity (RH):	0% <rh 80%<="" <="" td=""></rh>	
Atmospheric Pressure:	101.3kPa + 10 to –5 kPa	

3.2 RF characteristics of the test site

All HAC measurements were performed inside a shielded room that provide isolation from external EM fields, with the RF ambient at least 20 dB below the intended measurement limits.

3.3 Test Signal, Frequencies and Output Power

The device supports CDMA2000 in 1X (Phase I, Protocol revision 6) mode only. CDMA2000 1X includes TIA/EIA-95B as a subset and was approved for publishing in July 1999. It provides voice and data capabilities within a standard 1.25 MHz CDMA channel. This RF bandwidth is identical to the legacy IS-95 B system standard.

Peak and Average conducted power were measured to ensure worst case power configuration was tested:

CONFIGURATION		CONDUCTED POWER	
	(Full Rate)	CDMA 800 (ch 383)	CDMA 1900 (ch 600)
		Average (dBm)	Average (dBm)
SO2	RC1	25.22	24.8
	RC3	25.21	24.78
SO55	RC1	25.24	24.81
	RC3	25.3	24.85
SO32	RC3 (+ SCH) Full Rate	25.19	24.82
	RC3 (+ F-SCH)	25.3	24.85

In all operating modes, the phone was set to rated maximum RF power level and the measurements were performed on low, mid and high channels.

The measurement system measures power drift during HAC testing by comparing E/H-field in the same location at the beginning and at the end of measurement. These records were used to monitor stability of power output during tests. Conducted RF power measurements were also performed before and after each HAC measurements to confirm the output power.

During tests, the EUT was put in in-call mode and controlled by a CDMA simulator to generate the required signal and power:

Protocol:	6 (IS-2000)
Radio Configuration:	3

© 2009 Comptest Services LLC Page 5 of 24 HAC RF Report This report shall not be reproduced except in full, without the written consent of CompTest Services LLC.



Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

Power Control:	All Up Bits
Service Option:	55
Data Rate:	Full

3.4 EUT Operating Conditions

The EUT was tested with the follow configurations and conditions, if applicable:

X Fully charged standard battery as supplied with the handset

- X Close configuration at ear use position
- Both retracted and extended antenna positions
- X Back-light always ON
- X Simultaneous transmission with Bluetooth transmitter ON*

Note: *The Bluetooth transmitter was not enable during tests, since the intended use of the CDMA transmitter does not include support simultaneous operation when held to ear.



Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

4 DESCRIPTION OF TEST EQUIPMENT

4.1 Test Equipment Used

Below is a list of the calibrated equipment used for the measurements. The calibration certificates of E-field and H-field probes are attached in Appendix A.

Description	Manufacturer	Model Number	Serial Number	Cal Due Date
Power Meter	Giga-tronics	8541C	1831306	07/16/09
Signal Generator	Hewlett Packard	E4421B	US38440337	07/14/09
Radio Communication Tester	Agilent	8960	GB44052789	08/13/09
Data Acquisition	Speag	DAE4	530	04/15/10
E-field Probe	Speag	ER3DV6	2341	03/10/10
H-field Probe	Speag	H3DV5	6123	08/18/09
Dipole Antenna (835MHz)	Speag	CD835V3	1020	04/26/10
Dipole Antenna (1880MHz)	Speag	CD1880V3	1015	04/26/10

4.2 Near Field Measurement System

The measurements were performed with Dasy4 automated near-field scanning system comprised of high precision robot, robot controller, computer, near-field probe, probe alignment sensor, non-conductive phone positioner, Test Arch and software extension. The overall expanded uncertainty (K=2) of the measurement system is $\pm 10.9\%$ and $\pm 14.7\%$ for H-field and E-field resp. The measurement uncertainty budget is given in section 6.



Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

4.3 Isotropic E-	Field Probe
Model	 ER3DV6
Construction	 One dipole parallel, two dipoles normal to probe axis
	 Built-in shielding against static charges
	 PEEK enclosure material (resistant to organic solvents, e.g., glycolether)
Calibration	 In air from 100 MHz to 3.0 GHz (absolute accuracy ± 6%; k=2)
Frequency	 100MHz to 6 GHz
	 Linearity: ± 0.2dB (100MHz to 3GHz)
Directivity	 ± 0.2 dB in air (rotation around probe axis)
	 ± 0.4 dB in air (rotation normal to probe axis)
Dynamic Range	2 V/m to > 1000 V/m
	 Linearity: ± 0.2 dB
Dimensions	 Overall length: 330 mm (Tip: 16 mm)
	 Tip diameter: 8 mm (Body: 12 mm)
	 Distance from probe tip to dipole centers: 2.5 mm
Application	 General near-field measurements up to 6 GHz
	 Field component measurements
	 Fast automatic scanning in phantoms

4.4 Isotropic -Field	Probe
Model	 H3DV6
Construction	 Three concentric loop sensors with 3.8 mm loop diameters
	 Resistively loaded detector diodes for linear response
	 Built-in shielding against static charges
	 PEEK enclosure material (resistant to organic solvents, e.g., glycolether)
Frequency	 200 MHz to 3 GHz (± 6.0%, k=2); Output linearized
Directivity	 ± 0.25 dB (spherical isotropy error)
Dynamic Range	 10 mA/m to 2 A/m at 1 GHz
E-Field Interference	< 10% at 3 GHz (for plane wave)
Dimensions	 Overall length: 330 mm (Tip: 40 mm)
	 Tip diameter: 6 mm (Body: 12 mm)
	 Distance from probe tip to dipole centers: 3 mm
Application	 General magnetic near-field measurements up to 3 GHz
	 Field component measurements
	 Surface current measurements
	 Measurements in air or liquids
	 Low interaction with the measured field

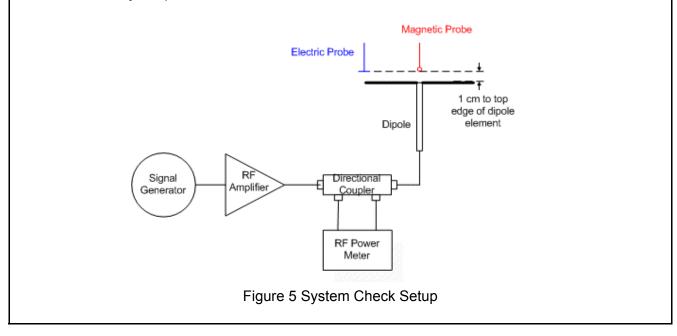


Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

5 SYSTEM VALIDATION

5.1 Dipole Validation Setup

The probes are calibrated annually by the manufacturer. The HAC measurements of the device were done within 24 hours of system accuracy verification, which was done using calibration dipoles. Unmodulated continous wave of power level of 20dBm was supplied to a dipole antenna placed under Test Arch. The measurement probes are positioned over the illuminated dipole at 10mm distance from the top surface of the dipole element to the calibration reference point of the sensor, defined by the probe manufacturer.





Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

5.2 Dipole Validation Results

The length of the dipole was scanned with both E and H-field probes and the maximum values for each were recorded. The validation results are in the table below and printouts of the validation test are attached in Appendix B. All the measured parameters were within the specification.

Freq. (MHz)	Parameter	Target (SPEAG)	Measured	Delta (%)	Limit (%)	Test date
835	E dB(V/m)	159.5	170.4	6.83	± 25	7/01/09
	H dB(A/m)	0.458	0.425	-7.25	± 25	6/30/09
	H dB(A/m)	0.458	0.435	-4.91	± 25	7/01/09
1880	E dB(V/m)	140.4	143.1	1.92	± 25	7/01/09
	H dB(A/m)	0.466	0.448	-3.95	± 25	6/30/09
	H dB(A/m)	0.466	0.446	-4.38	± 25	7/01/09



6 DESCRIPTION OF TEST PROCEDURE

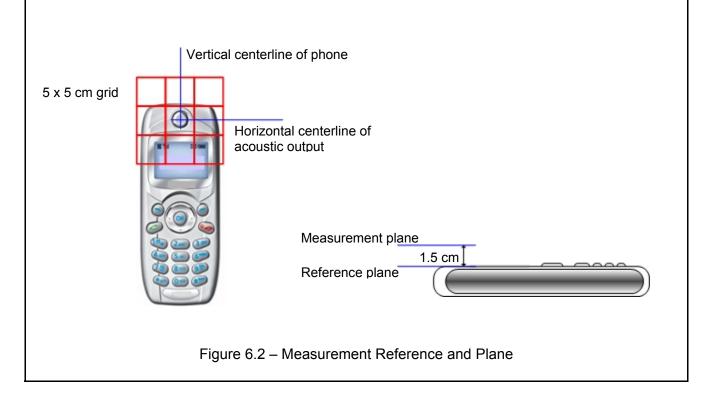
6.1 Test Positions

The device was placed on a non-conductive phone positioner under the Test Arch.

6.2 RF Emission Measurements Reference and Plane

Figure 6.2 illustrates the references and reference plane that shall be used in the EUT emissions measurement:

- The grid is 5 cm by 5 cm area that is divided into 9 evenly sized blocks or sub-grids.
- The grid is centered on the audio frequency output transducer (speaker) of the EUT.
- The grid is in a reference plane, which is defined as the planar area that contains the highest point in the area of the phone that normally rests against the user's ear. It is parallel to the centerline of the receiver of the EUT and is defined by the points of the receiver-end of the EUT, which, in normal handset use, rest against the ear.
- The measurement plane is parallel to, and 1.5 cm in front of, the reference plane.

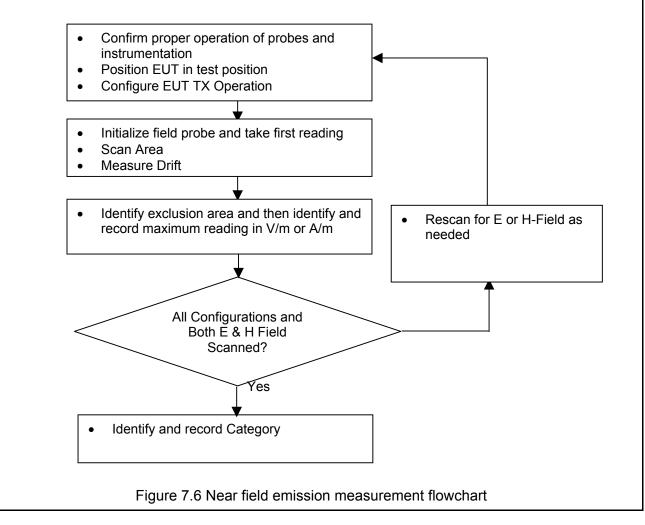




6.3 RF Emissions Measurement Procedures

Flowchart below shows the near field emission measurement:

- 1. The center of the probe was scan to the edges of the grid. Accordingly the total area covered by the outside edge of the probe was the 5 cm by 5 cm area, increased by half ($\frac{1}{2}$) the probe diameter on all sides.
- 2. The nearest point on the probe measurement element(s) was held 1.0 cm from the EUT reference plane.
- 3. The probe element is that portion of the probe that is designed to receive and sense the field being measured.
- 4. The physical body of the probe housing was not used when setting this 1.0 cm distance as this would place the sensing elements at an indeterminate distance from the reference plane.
- 5. The step size of the scan is set to 5 mm or less.
- 6. Up to three blocks were excluded for each field measurement.
 - The center block containing the EUT output was not excluded.
 - A maximum of five blocks were excluded for both E- and H-field measurements for the EUT output being measured. Stated differently, the center sub-grid or block and 3 other blocks were common to both the E- and H-field measurements for a given grid.



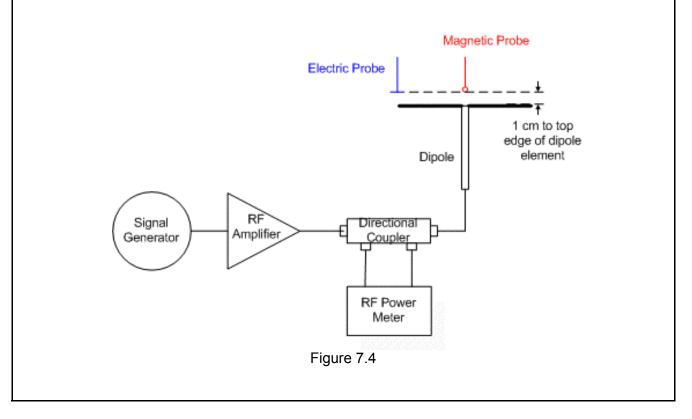


7 PROBE MODULATION FACTOR (PMF)

7.1 PMF Measurement Procedures

A calibration was made of the modulation response of the probe and its instrumentation chain. This calibration was performed with the field probe, attached to its instrumentation. The response of the probe system to a CW field at the frequency of interest is compared to its response to a modulated signal with equal peak amplitude to that of a CW signal. The field level of the test signals shall be more than 10 dB above the ambient level and the noise floor of the instrumentation being used. The ratio of the CW reading to that taken with a modulated reading was applied to the DUT measurements. The measurement procedures are as following:

- 1. Fix the field probe in a set location relative to the dipole antenna, as illustrated in Figure 7.4.
- 2. Setup the wireless device (EUT) with intended signal at the intended measurement frequency.
- 3. Record the reading of the probe measurement system.
- 4. Replace the wireless device with a RF signal generator producing an unmodulated CW signal and set to the wireless device operating frequency.
- 5. Set the peak power of the unmodulated signal to equal that recorded from the wireless device
- 6. Record the reading of the probe measurement system of the unmodulated CW signal.
- 7. The ratio of probe reading (CW) in step 6 to the probe reading (EUT) in step 3 is the modulation factor.





Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

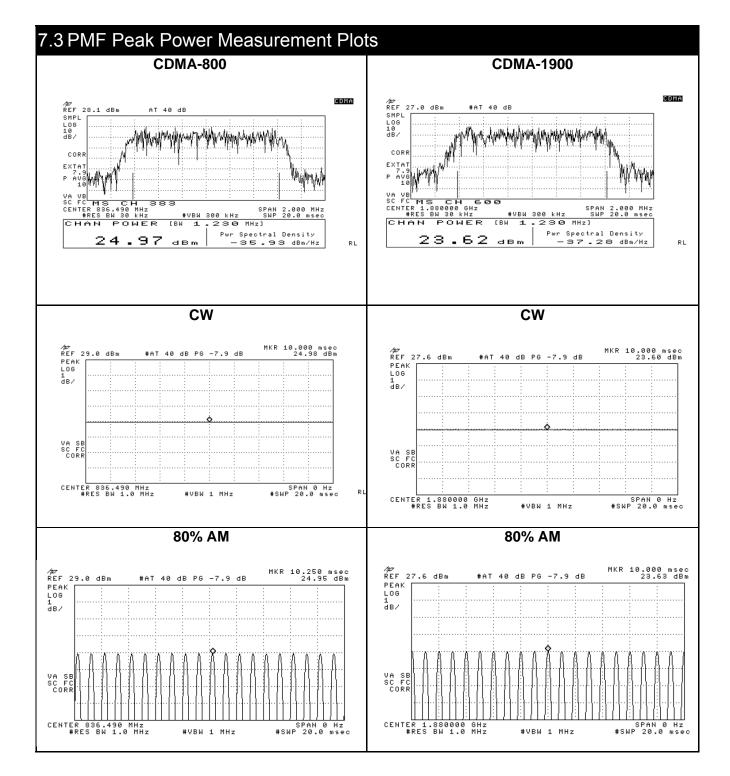
7.2 PMF Test Results

The modulation factors obtained by above method shall be applied to readings taken of the actual WD, in order to obtain an accurate peak field reading.

E-Field					
Frequency (MHz)	Peak Power (dBm)	Protocol	Protocol Reading (V/m)	Modulation Factor	
835	24.98	CW	103.9		
	24.97	CDMA (full rate)	106.3	0.98	
	24.95	AM	66.54	1.56	
1880	23.60	CW	70.76		
	23.62	CDMA (full rate)	73.12	0.97	
	23.63	AM	46.97	1.51	
		H-Field			
Frequency (MHz)	Peak Power (dBm)	Protocol	Protocol Reading (A/m)	Modulation Factor	
835	24.97	CW	0.312		
	24.95	CDMA (full rate)	0.319	0.98	
	24.94	AM	0.206	1.51	
1880	23.82	CW	0.294		
	23.81	CDMA (full rate)	0.305	0.96	
	23.83	AM	0.189	1.56	



Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0





8 EMISSION DATA EXTRACTION AND POSTPROCESSING

At the end of the measurements, the DASY4 system automatically evaluates the slot-averaged results, exclusion of the three highest subgrid, application of the AWF factor per ANSI-C63.19 requirements.

The following AWF factors were used for the standard transmission protocols:

Standard	Technology	AWF
TIA/EIA/IS-2000	CDMA	0
TIA/EIA-136	TDMA (50 Hz)	0
J-STD-007	GSM (217)	-5
T1/T1P1/3GPP	UMTS (WCDMA)	0
iDEN™	TDMA(22 and 11 Hz)	0

Table 8.1 Articulation Weighting Factor (AWF)

All DASY4 measurements are in RMS values. The Dasy4 system incorporates the crest factor of the signal in the computation of the RMS values. Although the software also has the capability to estimate the peak field by applying a square root of the crest factor value to the readings, the probe modulation factor was applied manually instead per ANSI C63.19 in the measurement tables in this report using equation:

Peak Field = (DASY4 reading) x PMF

where DASY4 reading = measurement from DASY4 in V/m or A/m PMF = Probe Modulation Factor in linear unit



Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

9 MEASUREMENT UNCERTAINTY

Table 8.1 shows the uncertainty budget for HAC free field assessment according to ANSI C63.19-2007. The budget is valid for the frequency range 800 MHz - 3 GHz and represents a worst-case analysis. For specific tests and configurations, the uncertainty could be smaller.

Uncertainty Description	Uncert . Value (± %)	Prob Dist.	Div.	C _i (E)	C _i (H)	Stand. Uncert (E) (±%)	Stand. Uncert (H) (±%)
Measurement system							
Probe calibration	5.1	Ν	1	1	1	5.1	5.1
Axial isotropy of the probe	4.7	R	√3	1	1	2.7	2.7
Sensor displacement	16.5	R	√3	1	0.14 5	9.5	1.4
Boundary effects	2.4	R	√3	1	1	1.4	1.4
Probe linearity	4.7	R	√3	1	1	2.7	2.7
Scaling to Peak Envelope Power	2.0	R	√3	1	1	1.2	1.2
System Detection limit	1.0	R	√3	1	1	0.6	0.6
Readout electronics	0.3	Ν	1	1	1	0.3	0.3
Response time	0.8	R	√3	1	1	0.5	0.5
Integration time	2.6	R	√3	1	1	1.5	1.5
RF ambient conditions	3.0	R	√3	1	1	1.7	1.7
RF Reflections	12	R	√3	1	1	6.9	6.9
Probe Positioner	1.2	R	√3	1	0.67	0.7	0.5
Probe positioning	4.7	R	√3	1	0.67	2.7	1.8
Extrap. and integration	1.0	R	√3	1	1	0.6	0.6
Test Sample Related							
Device positioning vertical	4.7	R	√3	1	0.67	2.7	1.8
Device Positioning Lateral	1.0	R	√3	1	1	0.6	0.6
Device Holder and Phantom	2.4	R	√3	1	1	1.4	1.4
Power drift	5.0	R	√3	1	1	2.9	2.9
Phantom and Setup Related							
Phantom thickness	2.4	R	√3	1	0.67	1.4	0.9
		ined St				14.7	10.9
Extended S						29.4	21.8
Extended N: Normal R: Rectangular	Standard	Uncert	ainty c	on Field	l (k=2):	14.7	10.9
Table 9.1 Wors	t-Case und	certainty	/ budg	et for H	AC free	field assess	nent



Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

10 RF EMISSIONS TESTS

10.1 Emission Limits

FCC: § 20.19, ANSI C63.19-2007

IC:

Table 10.1 shows the M-rating criteria from ANSCI C63.19. All digital transmission modes in all frequency bands contained in a HAC phone must meet M3 or M4 levels.

Near Field	Wireless Device RF Parameters [AWF = 0]					
Cotogony	E-Field E	missions	missions H-Field Emissions			
Category	dB(V/m) Peak	V/m Peak	dB(A/m) Peak	V/m Peak		
Freq < 960 MHz						
M1	56.0 to 61.0	631.0 to 1122.0	5.6 to 10.6	1.91 to 3.39		
M2	51.0 to 56.0	354.8 to 631.0	0.6 to 5.6	1.07 to 1.91		
М3	46.0 to 51.0	199.5 to 354.8	-4.4 to 0.6	0.60 to 1.07		
M4	< 46.0	< 199.5	< -4.4	< 0.60		
		Freq > 960 M	Hz			
M1	46.0 to 51.0	199.5 to 354.8	-4.4 to 0.6	0.60 to 1.07		
M2	41.0 to 46.0	112.2 to 199.5	-9.4 to -4.4	0.34 to 0.60		
M3	36.0 to 41.0	63.1 to 112.2	-14.4 to -9.4	0.19 to 0.34		
M4	< 36.0	< 63.1	< -14.4	< 0.19		

Table 10.1 RF Emission Limits



Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

10.2 CDMA 800 Test Results								
Configuration	on:	Open w	ith Standard I	Battery		Antenna	a: Fixed	
				CDMA 80	0 E-Field			
Ch.	Bac	cklight	Bluetooth	Power	Dasy4 Reading	PMF	Peak Field	Category
#				dBm	V/m		A/m	М
1013		ON	OFF	25.12	75.6	1.00	75.6	4
383		ON	OFF	25.30	81.6	1.00	81.6	4
777		ON	OFF	25.08	72.7	1.00	72.7	4
1013 (360)		ON	OFF	25.12	73.1	1.00	73.1	4
1013 (BT)		ON	ON	25.12	75.9	1.00	75.9	4
				CDMA 80	0 H-Field			
Ch.	Bac	cklight	Bluetooth	Power	Dasy4 Reading	PMF	Peak Field	Category
#				dBm	A/m		A/m	М
1013		ON	OFF	25.12	0.157	1.00	0.157	4
384		ON	OFF	25.30	0.145	1.00	0.145	4
777		ON	OFF	25.08	0.143	1.00	0.143	4
1013 (360)		ON	OFF	25.12	0.153	1.00	0.153	4
1013 (BT)		ON	ON	25.12	0.147	1.00	0.147	4



Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

10.3 CDMA 1900 Test Results								
Configuration	uration: Open with Standard Battery				Antenn	a:	Fixed	ł
			CDMA 1900	E-Field				
Ch.	Backlight	Bluetooth	Power	Dasy4 Reading	PMF	Pe Fie	ak eld	Category
#			dBm	V/m		A	'n	М
25	ON	OFF	24.66	32.6	1.00	32	2.6	4
600	ON	OFF	24.85	32.9	1.00	32	.9	4
1175	ON	OFF	24.70	38.8	1.00	38	8.8	4
1175 (360)	ON	OFF	24.70	36.9	1.00	36	6.9	4
1175 (BT)	ON	ON	24.70	38.8	1.00	38	8.8	4
			CDMA 1900	H-Field				
Ch.	Backlight	Bluetooth	Power	Dasy4 Reading	PMF	Pe Fie	ak eld	Category
#			dBm	A/m		A	'n	М
25	ON	OFF	24.66	0.096	1.00	0.0	96	4
600	ON	OFF	24.85	0.103	1.00	0.1	03	4
1175	ON	OFF	24.70	0.106	1.00	0.1	06	4
1175 (360)	ON	OFF	24.70	0.103	1.00	0.1	03	4
1175 (BT)	ON	ON	24.70	0.115	1.00	0.1	15	4



10.4 Worst-Case Configuration Evaluation

The probe was rotated 360° at Azimuth axis in the worst case configuration. The rotation was performed at the location of maximum field strength in the included blocks.

	CDMA 800 H-Field							
Config	uration:	Open with Standard Battery		Antenna:	Fixed			
Ch.	Backlight	Bluetooth	Conducted Power	Peak Field	PMF	Peak Field	Category	
#			dBm	A/m		A/m	М	
1013	ON	OFF	25.12	73.1	1.00	73.1	4	

CDMA 1900 E-Field							
Config	uration:	Open with St	andard Battery	Antenna:	Fixed		
Ch.	Backlight	Bluetooth	Conducted Power	Peak Field	PMF	Peak Field	Category
#			dBm	V/m		V/m	М
1175	ON	OFF	24.70	36.9	1.00	36.9	4

Data plots are shown in Appendix C



11 APPENDIX A: PROBE CALIBRATION CERTIFICATION

Engineering AG Zeughausstrasse 43, 8004 Zurio	ry of	ACCONTRA CONT	Service suisse d'étalonnage Servizio svizzero di taratura
Accredited by the Swiss Accredit The Swiss Accreditation Servic Multilateral Agreement for the r	e is one of the signatori	es to the EA	n No.: SCS 108
Client Kyocera USA			o: ER3-2341_Mar09
CALIBRATION	CERTIFICAT		
Object	ER3DV6 - SN:2	341	
Calibration procedure(s)	QA CAL-02.v5 Calibration proc evaluations in a	edure for E-field probes optimized Ir	l for close near field
Calibration date:	March 10, 2009		
Condition of the calibrated item	In Tolerance		
		tional standards, which realize the physical un probability are given on the following pages an	
The measurements and the unco	ertaintles with confidence providence for the closed laborate	probability are given on the following pages an ory facility: environment temperature $(22 \pm 3)^{\circ}$	d are part of the certificate.
The measurements and the unco All calibrations have been condu	ertaintles with confidence providence for the closed laborate	probability are given on the following pages an ory facility: environment temperature $(22 \pm 3)^{\circ}$	d are part of the certificate.
The measurements and the unco All calibrations have been condu Calibration Equipment used (M& Primary Standards Power meter E4419B	ertainties with confidence p ucted in the closed laborate TE critical for calibration) ID # GB41293874	probability are given on the following pages an ory facility: environment temperature (22 ± 3)°(Cal Date (Certificate No.) 1-Apr-08 (No. 217-00788)	nd are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09
The measurements and the unco All calibrations have been condu Calibration Equipment used (M& Primary Standards Power meter E4419B Power sensor E4412A	ertainties with confidence p acted in the closed laborate ATE critical for calibration) ID # GB41293874 MY41495277	probability are given on the following pages an ory facility: environment temperature (22 ± 3)°C Cal Date (Certificate No.) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788)	nd are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09
The measurements and the unce All calibrations have been condu Calibration Equipment used (M8 Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A	ertainties with confidence p inceed in the closed laborate ID # GB41293874 MY41495277 MY41498087	probability are given on the following pages an ory facility: environment temperature (22 ± 3)°C Cal Date (Certificate No.) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788)	d are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09 Apr-09
The measurements and the unce All calibrations have been condu Calibration Equipment used (M& Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator	ertainties with confidence placed in the closed laborate TE critical for calibration) ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c)	probability are given on the following pages an ory facility: environment temperature (22 ± 3)°C Cal Date (Certificate No.) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Jul-08 (No. 217-00788) 1-Jul-08 (No. 217-00865)	d are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09 Apr-09 Jul-09
The measurements and the unce All calibrations have been condu Calibration Equipment used (M& Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator	ertainties with confidence p incred in the closed laborate ATE critical for calibration) ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b)	probability are given on the following pages an ory facility: environment temperature (22 ± 3)°(<u>Cal Date (Certificate No.)</u> 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Jul-08 (No. 217-00788) 31-Mar-08 (No. 217-00787)	ad are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09 Apr-09 Jul-09 Jul-09 Apr-09
The measurements and the unco All calibrations have been condu Calibration Equipment used (M& Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 30 dB Attenuator	ertainties with confidence p incred in the closed laborator ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5056 (20b) SN: S5129 (30b)	probability are given on the following pages an ory facility: environment temperature (22 ± 3)°(<u>Cal Date (Certificate No.)</u> 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Jul-08 (No. 217-00786) 31-Mar-08 (No. 217-00787) 1-Jul-08 (No. 217-00786)	ad are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09 Jul-09 Apr-09 Jul-09 Jul-09
The measurements and the unco All calibrations have been condu Calibration Equipment used (M8 Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6	ertainties with confidence p ucted in the closed laborator TE critical for calibration) ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5056 (20b) SN: S5129 (30b) SN: 2328	probability are given on the following pages an ory facility: environment temperature (22 ± 3)°(<u>Cal Date (Certificate No.)</u> 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Jul-08 (No. 217-00786) 31-Mar-08 (No. 217-00787) 1-Jul-08 (No. 217-00865) 1-Oct-08 (No. ER3-2328_Oct08)	ad are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09 Jul-09 Jul-09 Jul-09 Jul-09 Oct-09
The measurements and the unco All calibrations have been condu Calibration Equipment used (M& Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 30 dB Attenuator	ertainties with confidence p incred in the closed laborator ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5056 (20b) SN: S5129 (30b)	probability are given on the following pages an ory facility: environment temperature (22 ± 3)°(<u>Cal Date (Certificate No.)</u> 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Jul-08 (No. 217-00786) 31-Mar-08 (No. 217-00787) 1-Jul-08 (No. 217-00786)	ad are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09 Jul-09 Apr-09 Jul-09 Jul-09
The measurements and the unco All calibrations have been condu Calibration Equipment used (M8 Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6	ertainties with confidence p ucted in the closed laborator TE critical for calibration) ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5056 (20b) SN: S5129 (30b) SN: 2328	probability are given on the following pages an ory facility: environment temperature (22 ± 3)°(<u>Cal Date (Certificate No.)</u> 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Jul-08 (No. 217-00786) 31-Mar-08 (No. 217-00787) 1-Jul-08 (No. 217-00865) 1-Oct-08 (No. ER3-2328_Oct08)	ad are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09 Jul-09 Jul-09 Jul-09 Jul-09 Oct-09
The measurements and the unce All calibrations have been condu Calibration Equipment used (M& Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6 DAE4	ID # GB41293874 MY41495277 MY41495277 MY41498087 SN: S5054 (3c) SN: S5054 (3c) SN: S5054 (3c) SN: S5129 (30b) SN: S5129 (30b) SN: 789	Cal Date (Certificate No.) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Jul-08 (No. 217-00788) 1-Jul-08 (No. 217-00787) 1-Jul-08 (No. 217-00787) 1-Jul-08 (No. 217-00865) 31-Mar-08 (No. 217-00865) 1-Oct-08 (No. 217-00866) 1-Oct-08 (No. DAE4-789_Dec08)	ad are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09 Jul-09 Jul-09 Oct-09 Dec-09
The measurements and the unce All calibrations have been condu Calibration Equipment used (M& Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 30 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Sændards	ertainties with confidence incled in the closed laborate ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5054 (3c) SN: S5056 (20b) SN: S5129 (30b) SN: 2328 SN: 789 ID #	probability are given on the following pages and ory facility: environment temperature (22 ± 3)°C Cal Date (Certificate No.) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Jul-08 (No. 217-00788) 1-Jul-08 (No. 217-00787) 1-Jul-08 (No. 217-00787) 1-Jul-08 (No. 217-00865) 1-Oct-08 (No. 217-00865) 1-Oct-08 (No. ER3-2328_Oct08) 19-Dec-08 (No. DAE4-789_Dec08) Check Date (in house)	ad are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09 Jul-09 Jul-09 Jul-09 Oct-09 Dec-09 Scheduled Check
The measurements and the unce All calibrations have been condu Calibration Equipment used (M& Primary Standards Power sensor E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 30 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Sendards RF generator hP 8648C	ertainties with confidence incled in the closed laborate ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5054 (3c) SN: S5054 (3c) SN: S5129 (30b) SN: 2328 SN: 789 ID # US3642U01700	Cal Date (Certificate No.) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Jul-08 (No. 217-00788) 1-Jul-08 (No. 217-00787) 1-Jul-08 (No. 217-00865) 1-Oct-08 (No. 217-00865) 1-Oct-08 (No. 217-00865) 1-Oct-08 (No. 217-00865) 1-Cector (No. DAE4-789_Dec08) Check Date (in house) 4-Aug-99 (in house check Oct-07)	ad are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09 Jul-09 Jul-09 Jul-09 Oct-09 Dec-09 Scheduled Check In house check: Oct-09
The measurements and the unce All calibrations have been condu Calibration Equipment used (M& Primary Standards Power sensor E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 30 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Sendards RF generator hP 8648C	ertainties with confidence incted in the closed laborate ID # GB41293874 MY41495277 MY41495277 MY41498087 SN: S5054 (3c) SN: S5054 (3c) SN: S5056 (20b) SN: S5129 (30b) SN: 2328 SN: 789 ID # US3642U01700 US37390585	Cal Date (Certificate No.) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Jul-08 (No. 217-00788) 1-Jul-08 (No. 217-00786) 1-Jul-08 (No. 217-00787) 1-Jul-08 (No. 217-00865) 31-Mar-08 (No. 217-00865) 1-Oct-08 (No. ER3-2328_Oct08) 19-Dec-08 (No. DAE4-789_Dec08) Check Date (in house) 4-Aug-99 (in house check Oct-07) 18-Oct-01 (in house check Oct-08)	ad are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09 Jul-09 Jul-09 Jul-09 Oct-09 Dec-09 Scheduled Check In house check: Oct-09 In house check: Oct-09
The measurements and the unce All calibrations have been condu Calibration Equipment used (M& Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 3 dB Attenuator Reference 3 dB Attenuator Reference 3 dB Attenuator Reference 9 dB Attenuator Reference 9 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Sændards RF generator 14P 8648C Network Analyzer HP 8753E	ertainties with confidence incted in the closed laborate ID # GB41293874 MY41495277 MY41495277 MY41498087 SN: S5054 (3c) SN: S5056 (20b) SN: S5129 (30b) SN: S5129 (30b) SN: 2328 SN: 789 ID # US3642U01700 US37390585 Name	Cal Date (Certificate No.) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Apr-08 (No. 217-00788) 1-Jul-08 (No. 217-00788) 1-Jul-08 (No. 217-00786) 1-Jul-08 (No. 217-00787) 1-Jul-08 (No. 217-00865) 31-Mar-08 (No. 217-00865) 1-Oct-08 (No. ER3-2328_Oct08) 19-Dec-08 (No. DAE4-789_Dec08) Check Date (in house) 4-Aug-99 (in house check Oct-07) 18-Oct-01 (in house check Oct-08) Function	ad are part of the certificate. C and humidity < 70%. Scheduled Calibration Apr-09 Apr-09 Jul-09 Jul-09 Jul-09 Oct-09 Dec-09 Scheduled Check In house check: Oct-09 In house check: Oct-09

Certificate No: ER3-2341_Mar09

Page 1 of 9



Applicant:	Kyocera
FCC ID:	V65SCP-6760
Report #:	CT-6760-20RF-0709-R0

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





s Schweizerischer Kalibrierdienst

Service suisse d'étalonnage

С Servizio svizzero di taratura s

Swiss Calibration Service

Accreditation No.: SCS 108

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Client Kyocera USA		C C	ertificate No: H3=6123_Aug08
GALIBRATION GERITIE GALE			
Object	H3DV6-SN:61	23	
Calibration procedure(s)	CA CAL-03:v5 Calibration proc evaluations in a	edure for H-field probes o ir	optimized for close near field
Calibration date:	August 18, 2008	8	
Condition of the calibrated item	in Tolerance		
This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate. All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.			
Calibration Equipment used (M&TE critical for calibration)			
Primary Standards	ID#	Cal Date (Certificate No.)	Scheduled Calibration
Power meter E4419B	GB41293874	1-Apr-08 (No. 217-00788)	Apr-09
Power sensor E4412A	MY41495277	1-Apr-08 (No. 217-00788)	Apr-09
Power sensor E4412A	MY41498087	1-Apr-08 (No. 217-00788)	Apr-09
Reference 3 dB Attenuator	SN: S5054 (3c)	1-Jul-08 (No. 217-00865)	Jul-09
Reference 20 dB Attenuator	SN: S5086 (20b)	31-Mar-08 (No. 217-00787)	Apr-09
Reference 30 dB Attenuator Reference Probe H3DV6	SN: S5129 (30b) SN: 6182	1-Jul-08 (No. 217-00866)	Jul-09 Oct-08
DAE4	SN: 654	2-Oct-07 (No. H3-6182_Oct07) 24-Apr-08 (No. DAE4-654_Apr	
	1 914: 004	2+-spirod (No. BAE+-bo+_spi	
Secondary Standards	ID #	Check Date (in house)	Scheduled Check
RF generator HP 8648C	US3642U01700	4-Aug-99 (in house check Oct-	07) In house check: Oct-09
Network Analyzer HP 8753E	U\$37390585	18-Oct-01 (in house check Oct	-07) In house check: Oct-08
Calibrated by:	Name Katja Poković	Function Technical Manage	Signature
			and the second
Approved by:	Niels Kuster	Quality Manager	11/205
			Issued: August 25, 2008
This calibration certificate shall not be reproduced except in full without written approval of the laboratory.			

Certificate No: H3-6123_Aug08

Page 1 of 9

© 2009 Comptest Services LLC Page 23 of 24 HAC RF Report This report shall not be reproduced except in full, without the written consent of CompTest Services LLC.



12 APPENDIX B: SYSTEM VALIDATION DATA PLOTS

(See attachment)

13 APPENDIX C: TEST RESULTS/PLOTS

(See attachment)

14 APPENDIX D: PHOTO TEST SETUP

(see attachment)